

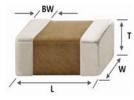
Specification of Automotive MLCC (Referance sheet)



- Supplier : Samsung Electro-Mechanics
- Product : Multi-layer Ceramic Capacitor
- Samsung P/N : CL21B475KOQVPNE
- Description : CAP, 4.7/ ♣, 16V, ± 10%, X7R, 0805
- AEC-Q200 Qualified

A. Dimension





Size	0805 inch	
L	2.00±0.15 mm 1.25±0.15 mm	
W		
Т	1.25±0.15 mm	
BW	0.50+0.20/-0.30 mm	

B. Samsung Part Number

<u>CL</u>	<u>21</u>	<u>B</u>	<u>475</u>	<u>ĸ</u>	<u>o</u>	<u>Q</u>	<u>v</u>	<u>P</u>	<u>N</u>	E
1	2	3	4	5	6	\bigcirc	8	9	10	1

1 Series	ries Samsung Multi-layer Ceramic Capacitor			
② Size	0805 (inch code)	L: 2.00±0.15 mm	W :1.25±0.15 mm	
③ Dielectric	X7R	Inner electrode	Ni	
④ Capacitance	4.7 μF	Termination	Metal-Epoxy	
5 Capacitance	± 10%	Plating	Sn 100% (Pb Free)	
tolerance		9 Product	Automotive	
⑥ Rated Voltage	16 V	Special code	Normal	
⑦ Thickness	1.25±0.15 mm	① Packaging	Embossed Type, 7" Reel	

C. Reliability Test and Judgement condition

Test items	Performance	Test condition		
High Temperature Appearance : No abnormal exterior appearance Ur		Unpowered, 1,000hrs @ Max. temperature		
Exposure	Capacitance Change Within ±10 %	Measurement at 24±2hrs after test conclusion		
	Tan δ :0.125 max.			
	IR∶More than 10,000 ^M Ω or 50 ^M Ω× <i>μ</i> F	Initial Measurement 2*		
	Whichever is smaller	Final Measurement 3*		
Temperature Cycling	Appearance : No abnormal exterior appearance	1,000Cycles		
	Capacitance Change Within ±10 %	Initial Measurement 2*		
	Tan δ :0.125 max.	Final Measurement 3*		
	IR : More than 10,000 ^{MQ} or 50 ^{MQ} × μ F	Measurement at 24±2hrs after test conclusion		
	Whichever is smaller	1 cycle condition : -55+0/-3 $^{\circ}$ C(30±3min) → Room Temp. (1min)		
		→ 125+3/-0 $^{\circ}$ C (30±3min) → Room Temp. (1min)		
Destructive Physical	No Defects or abnormalities	Per EIA 469		
Analysis				
Humidity Bias	Appearance : No abnormal exterior appearance	1,000hrs 85℃/85%RH, Rated Voltage and 1.3~1.5V,		
	Capacitance Change Within ±12.5 %	Add 100kohm resistor		
	Tan δ :0.125 max.	Initial Measurement 2*		
	IR : More than 500 $^{M\Omega}$ or 5 $^{M\Omega}$ × μ F	Final Measurement 4*		
	Whichever is smaller	Measurement at 24±2hrs after test conclusion		
		The charge/discharge current is less than 50mA.		
High Temperature	Appearance : No abnormal exterior appearance	1,000hrs @ 125 °C,150% Rated Voltage,		
Operating Life	Capacitance Change Within ±12.5 %	Initial Measurement 2*		
	Tan δ :0.125 max.	Final Measurement 4*		
	IR∶More than 1,000 ^M Ω or 5 ^M Ω× <i>μ</i> F	Measurement at 24±2hrs after test conclusion		
	Whichever is smaller	The charge/discharge current is less than 50mA.		
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	Performance	Test condition				
External Visual No abnormal exterior appearance		Microscope ('10)				
Physical Dimension	Within the specified dimensions	Using The calipers				
Mechanical Shock	Appearance : No abnormal exterior appearance	Three shocks in each direction should be applied along				
	Capacitance Change Within ±10 %	3 mutually perpendicular axes of the test specimen (18 shocks)				
	Tan δ, IR : Initial spec.	Peak value Duration Wave Velocity				
		1,500G 0.5ms Half sine 4.7m/sec				
		Initial Measurement 2*				
		Final Measurement 5*				
Vibration	Appearance : No abnormal exterior appearance	5g's for 20min., 12cycles each of 3 orientations,				
	Capacitance Change Within ±10 %	Use 8"×5" PCB 0.031" Thick 7 secure points on one long side				
	Tan δ, IR : Initial spec.	and 2 secure points at corners of opposite sides. Parts mounted				
		within 2" from any secure point. Test from $10~2,000$ Hz.				
		Initial Measurement 2*				
		Final Measurement 5*				
Resistance to	Appearance : No abnormal exterior appearance	preheating : 150°C for 60~120 sec.				
Solder Heat	Capacitance Change Within ±10 %	Solder pot : 260±5℃, 10±1sec.				
	Tan δ, IR : Initial spec.	Initial Measurement 2*				
		Final Measurement 3*				
ESD	Appearance : No abnormal exterior appearance	AEC-Q200-002 or ISO/DIS10605				
	Capacitance Change Within ±10 %	Initial Measurement 2*				
	Tan δ, IR : Initial spec.	Final Measurement 4*				
Solderability	95% of the terminations is to be soldered	a) Preheat at 155 $^\circ\!\!\!\!\!^\circ$ for 4 hours, Immerse in solder for 5s at 245±5 $^\circ\!\!\!\!^\circ\!\!\!^\circ$				
	evenly and continuously	b) Steam aging for 8 hours, Immerse in solder for 5s at 245 \pm 5 °C				
		c) Steam aging for 8 hours, Immerse in solder for 120s at 260±5 °C				
		solder : a solution ethanol and rosin				
	Capacitance : Within specified tolerance	*A capacitor prior to measuring the capacitance is heat treated at				
Characterization	Tan δ :0.1 max.	150 +0/-10°C for 1hour and maintained in ambient air for 24±2 hours				
	IR(25 [°] C) : More than 10,000 ^M Ω or 50 ^M Ω×μ ^F	The Capacitance / D.F. should be measured at 25° C,				
	Whichever is smaller	1 kHz ± 10%, 1 ± 0.2 Vrms				
	IR(125 °C) More than 1,000 M $_{\Omega}$ or 10 M $_{\Omega} \times \mu$ F	I.R. should be measured with a DC voltage not exceeding				
	Whichever is smaller	Rated Voltage @25°C, @125°C for 60~120 sec.				
	Dielectric Strength	Dielectric Strength : 250% of the rated voltage for 1~5 seconds				
Board Flex	Appearance : No abnormal exterior appearance	Bending to the limit, 3 mm for 60 seconds 1*				
	Capacitance Change Within ±10 %	Initial Measurement 2*				
		Final Measurement 5*				
Terminal	Appearance : No abnormal exterior appearance	18 N, for 60 sec.				
Strength(SMD)	Capacitance Change Within ±10 %	Initial Measurement 2*				
		Final Measurement 5*				
Beam Load	Destruction value should be exceed 20 N	Beam speed : 0.5±0.05 mm/sec				
- ·	X7R	1				
Temperature						

D. Recommended Soldering method :

Reflow (Reflow Peak Temperature : 260 +0/-5 °C , 30sec.), Meet IPC/JEDEC J-STD-020 D Standard

- *1 : The figure indicates typical specification. Please refer to individual specifications.
- *2 : Initial measurement : Perform a heat treatment at 150 +0/-10 °C for one hour after soldering process. and then let sit for 24±2 hours at room temperature. Perform the initial measurement.
- *3 : Final measurement : Let sit for 24±2 hours at room temperature after test conclusion, then measure.
- *4 : Final measurement : Perform a heat treatment at 150 +0/-10 °C for one hour after soldering process. and then let sit for 24±2 hours at room temperature. Perform the initial measurement.
- *5 : Final measurement : Let measure within 24 hours at room temperature after test conclusion.

A Product specifications included in the specifications are effective as of March 1, 2013.

Please be advised that they are standard product specifications for reference only.

We may change, modify or discontinue the product specifications without notice at any time.

So, you need to approve the product specifications before placing an order.

Should you have any question regarding the product specifications, please contact our sales personnel or application engineers.

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The products listed in this Specification sheet are **NOT** designed and manufactured for any use and applications set forth below.

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- Aerospace/Aviation equipment
- ② Medical equipment
- *③ Military equipment*
- ④ Disaster prevention/crime prevention equipment
- *5* Power plant control equipment
- 6 Atomic energy-related equipment
- ⑦ Undersea equipment
- ⑧ Traffic signal equipment
- Data-processing equipment
- 10 Electric heating apparatus, burning equipment
- ${\it I\!\! D}$ Safety equipment
- 2 Any other applications with the same as or similar complexity or reliability to the applications